

65V N-Channel Enhancement Mode MOSFET

Description

The AP60N06NF uses advanced **APM-SGTIT** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

V_{DS} = 65V I_D =60A

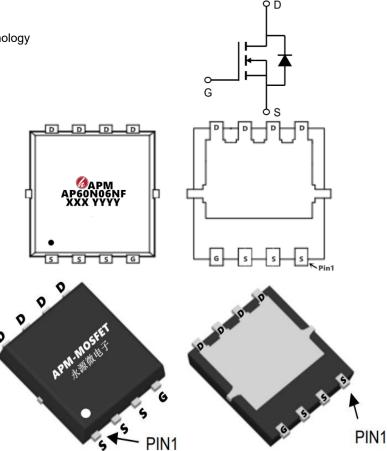
R_{DS(ON)} < 13mΩ @ V_{GS}=10V (Type: 9.5mΩ)

Application

Battery protection

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP60N06NF	PDFN5*6-8L	AP60N06NF XXX YYYY	5000

Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	65	V
VGS	Gate-Source Voltage	±20	V
I₀@Tc=25℃	Continuous Drain Current ^{1,6}	60	A
I₀@Tc=100°C	Continuous Drain Current ^{1,6}	24	A
IDM	Pulsed Drain Current ²	180	A
EAS	Single Pulse Avalanche Energy ³	20	mJ
P₀@Tc=25℃	Total Power Dissipation ⁴	31	W
TSTG	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
R₀JA	Thermal Resistance Junction-Ambient ¹	4.0	°C/W
R₀JC	Thermal Resistance Junction-Case ¹	85	°C/W

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Electrical Characteristics (TJ=25°C, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250µA	65	72	-	V
IGSS	Gate-body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
IDSS TJ=25°C					1	μA
IDSS TJ=100°C	Zero Gate Voltage Drain Current	V_{DS} =65V, V_{GS} =0V			100	
VGS(th)	Gate-Threshold Voltage	V_{DS} = V_{GS} , I_D =250 μ A	1.2	1.7	2.5	V
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} =10V, I _D =20A	-	9.5	13	mΩ
RDS(on)	Drain-Source On-Resistance ⁴	V _{GS} =4.5V, I _D =10A		13	18	mΩ
gfs	Forward Transconductance ⁴	V _{DS} = 10V, I _D = 10A	-	81	-	S
Ciss	Input Capacitance		-	731	-	
Coss	Output Capacitance	V _{DS} =30V,V _{GS} =0V, f =1MHz	-	224	-	pF
Crss	Reverse Transfer Capacitance		-	7.4	-	
Rg	Gate Resistance	f=1MHz	-	2.5	-	Ω
Qg	Total Gate Charge		-	13.9	-	
Qgs	Gate-Source Charge	V _{GS} =10V, V _{DS} =30V, I _D = 20A	-	1.6	-	nC
Qgd	Gate-Drain Charge		-	3.1	-	
td(on)	Turn-On Delay Time		-	3.7	-	
tr	Rise Time	V _{GS} =10V, V _{DD} =30V,	-	4.3	-	
td(off)	Turn-Off Delay Time	R_{G} = 1.5 Ω , I_{D} =15A	-	16.2	-	ns
t _f	Fall Time		-	6.5	-	
trr	Body Diode Reverse Recovery Time	L15A_dl/dt-100A/up	-	24	-	ns
Qrr	Body Diode Reverse Recovery Charge	l⊧=15A, dl/dt=100A/µs	-	9.3	-	nC
VSD	Diode Forward Voltage ⁴	I _S =15A, V _{GS} = 0V	-	-	1.2	V
IS	Continuous Source Current	T _A =25°C	-	-	65	Α

Note

 $1_{\mbox{\tiny V}}$ The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.

 $2\,{\scriptstyle\searrow}\,$ The data tested by pulsed , pulse width $\leq 300 us$, duty cycle $\leq 2\%$

3、The EAS data shows Max. rating . The test condition is VDD=48V,VGS=10V,L=0.1mH,IAS=18A

4. The power dissipation is limited by 150°C junction temperature

5. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation

N



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Typical Characteristics

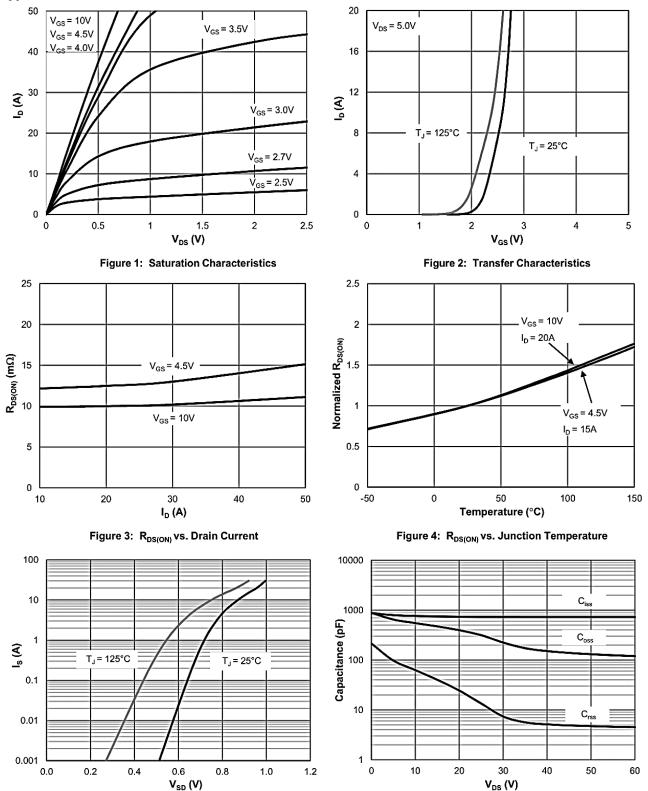


Figure 5: Body-Diode Characteristics

Figure 6: Capacitance Characteristics



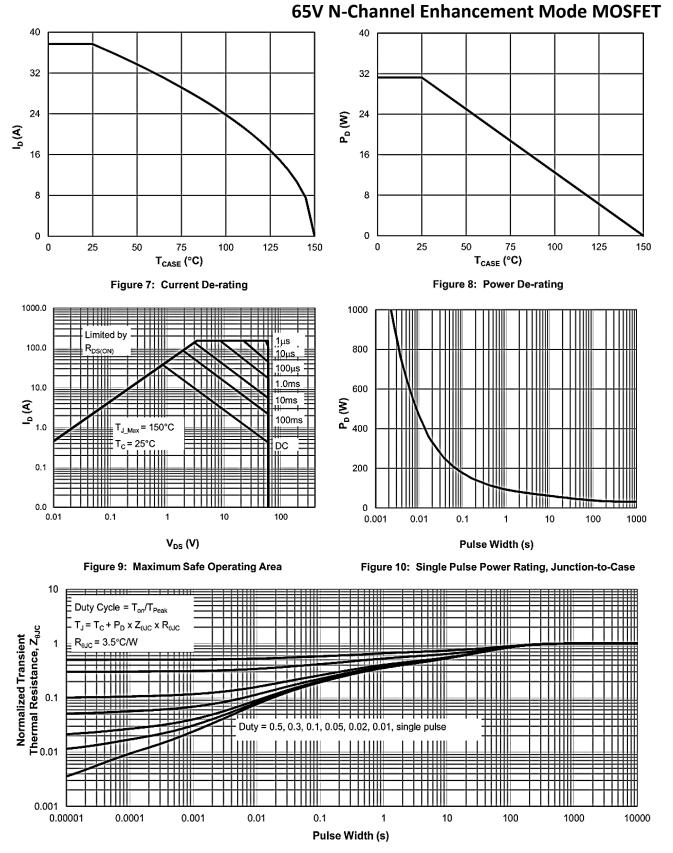
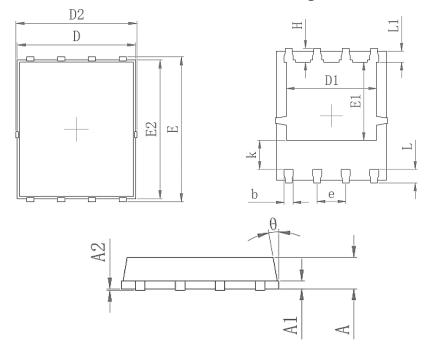


Figure 11: Normalized Maximum Transient Thermal Impedance

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65V N-Channel Enhancement Mode MOSFET Package Mechanical Data-PDFN5X6-8L-XZT Single



	Com	mon	
Symbol	mm		
	Mim	Max	
А	0.90	1.10	
A1	0.254	0.254 REF	
A2	0-0	0-0.05	
D	4.824	4.976	
D1	3.910	4.110	
D2	4.944	5.076	
E	5.924	6.076	
E1	3.375	3.575	
E2	5.674	5.826	
b	0.350	0.450	
е	1.2	1.270	
L	0.534	0.686	
L1	0.424	0.576	
К	1.190	1.390	
Н	0.549	0.701	
Φ	8 °	12°	

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<u>AP60N06NF</u>

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Edition	Date	Change
REV1.0	2023/8/1	Initial release

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